

# Calculation of the Via-Plate Capacitance of a Via with Pad Using Finite Difference Method for Signal/Power Integrity Analysis

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**Abstract**—Finite difference method is used to calculate the via-plate capacitances for vias with pad. Due to the symmetric structure, the solving domain is reduced to a rectangular  $\rho - z$  region. Boundary conditions along the region are discussed. Both barrel-plate and pad-plate capacitances are studied with various geometric parameters. The results could be used as validations for possible analytical expressions of these capacitances.

## I. INTRODUCTION

Vias are widely used, tinny structures connecting traces and planes in different layers of a multilayer printed circuit boards or packages. As an inevitable discontinuities along traces and sources for simultaneous switching noise along power/ground planes, accurate model for vias is critical for both signal integrity and power integrity analyses.

The parasitic capacitance between a via and the surrounding plate has been extensively studied using both numerical and analytical analysis [1]-[3]. However, these studies are usually for a via crossing a single plate, and the parasitic capacitance is called 'excess capacitance' used in a  $\pi$ -type circuit model for the via lumped circuit model.

Recently, a physics-based via circuit model is proposed for signal link path analysis and its feasibility has been demonstrated[4][5]. In this model, a via is represented as a  $\pi$ -type circuit where the via barrel is a short circuit; two via-plate capacitances are used to describe the displacement current from the via barrel to top/bottom planes and the impedance between two planes is used to denote the return current path. The impedance of parallel planes has been extensively studied. On the other hand, an analytical formula has been derived for the evaluation of the via-plate capacitance. Formula in [6], however, is only valid for those vias without a pad, *i.e.* with same barrel and pad radius.

In this paper, quasi-static finite difference method (FDM) is used to calculate the via-plate capacitance for the vias with different pad and barrel radius. Due to the symmetry of the via circular structure, the solving domain is reduced to a two dimensional rectangular region. The impact of the pad on the via-plate capacitance will be discussed. It will also provide a validation tool for the possible analytical expression for a via with pad.

## II. THE NUMERICAL METHOD FOR THE BARREL-PLATE CAPACITANCE OF A VIA WITH PAD

Fig. 1 shows a via with pad crossing two parallel planes. The barrel, pad and anti-pad radii are  $r$ ,  $a$  and  $b$ , respectively. The separation of two planes is  $h$ . Between the planes is the dielectric material with a permittivity of  $\epsilon_r$ . Due to the reason

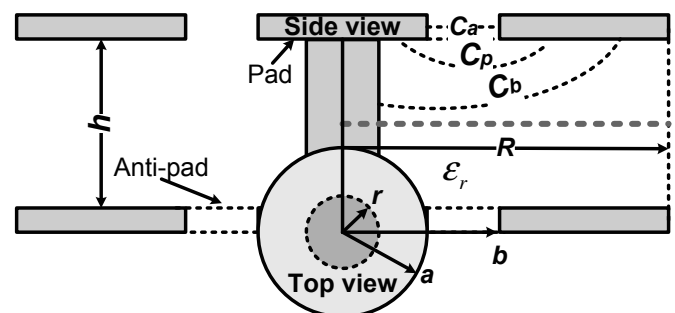


Fig. 1. Geometry of a via crossing a plane pair.

discussed in [5] and [6], the middle surface between two planes as shown in Fig. 1 satisfies the boundary condition of a perfect magnetic conductor (PMC). Moreover, the circular symmetry of the via structure can further reduce the solving domain into a rectangular region in  $\rho - z$  plane where  $\rho \in [r, R]$  and  $z \in [0, h/2]$  as shown in Fig.2. The artificial boundary  $\rho = R$  is chosen to terminate the solving domain. Since the static field decay inversely from sources, the final capacitance would converge when  $\rho = R$  is far away from the anti-pad. From our simulation,  $R \geq 3 \max\{b, h\}$  is a practical selection for acceptable simulation.

Fig. 2 indicates that for a via with a pad, there not only has the barrel-plate capacitance  $C_b$  but also the pad-plate capacitance  $C_p$ . The total capacitance from the via to the plate should be the summation of  $C_b$  and  $C_p$ . The coaxial capacitance  $C_a$  can be obtained using analytically as the transverse electromagnetic mode is assumed in the anti-pad. Therefore, only  $C_b$  and  $C_p$  are discussed here.



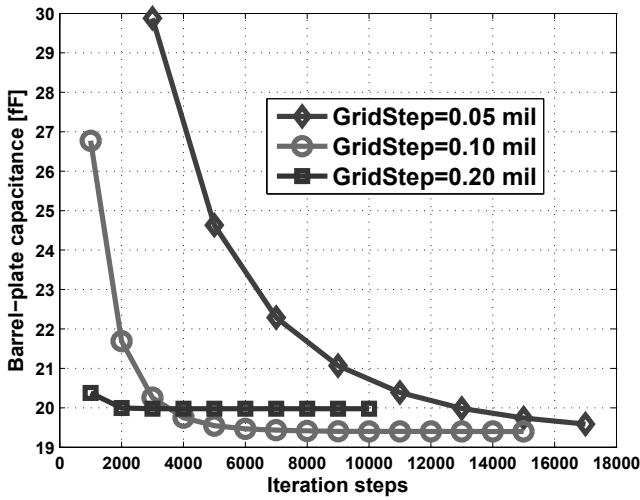


Fig. 3. Convergence of the barrel-plate capacitance calculation using the finite difference method. ( $r = a = 4, b = 14, h = 4.5$ , Unit : mil;  $\epsilon_r = 3.84$ )

simulations, the meshing grid step is selected to be 0.1 mil and the iteration number is set to be 7000.

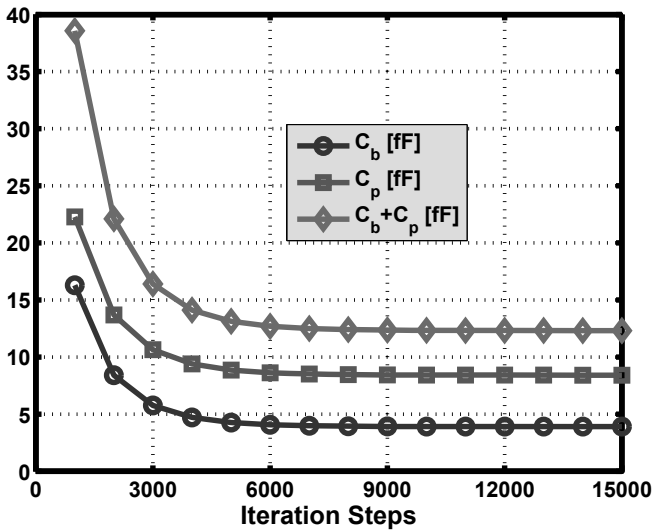


Fig. 4. Convergence of the barrel-plate, the pad-plate and total via capacitances ( $C_b, C_p$  and  $C_b + C_p$ ). ( $r = 4, a = 8, b = 20, h = 4.5$ , Unit : mil;  $\epsilon_r = 3.84$ )

Table. I compares the via-plate capacitances obtained by the 3-D commercial software (CST EM Studio), the analytical formula as well as the 2-D finite difference method here. It can be seen that the results from FDM with 7000 iteration steps agree very well with the results using the analytical solutions (less than 3% differences). Moreover, the 2D FDM is much faster than the 3D commercial electro-static solver although it is very slower than the analytical formula derived in [6]. These examples demonstrate the accuracy of the FDM

TABLE I

COMPARISON OF THE CONCENTRIC VIA-PLATE CAPACITANCE VALUE CALCULATED BY ELECTROSTATIC SOLVER, CST EM STUDIO, THE ANALYTICAL FORMULA OF [6] AND THE FDM PROPOSED HERE ( $h_u = h_d = 0.2286$  MM (9 MILS),  $t = 0.0254$  MM (1 MIL);  $\epsilon_r = 3.84$ .)

case	radii (mm)		$C_{via}$ (fF) (Elapsed time:seconds)		
	$a$	$b$	CST EM Studio	[6]	FDM
1	0.1016	0.3556	40.7 (303)	42.6 (0.15)	43.2 (27.8)
2	0.1016	0.4318	36.2 (301)	37.2 (0.15)	37.7 (34.4)
3	0.1016	0.5080	32.8 (308)	33.4 (0.15)	34.1 (41.2)
4	0.1524	0.3556	58.2 (380)	61.7 (0.15)	62.9 (26.0)
5	0.1524	0.4318	48.9 (365)	51.2 (0.15)	52.3 (33.1)
6	0.1524	0.5080	43.2 (308)	44.6 (0.15)	45.6 (39.2)
7	0.2032	0.3556	84.7 (431)	89.6 (0.15)	91.6 (24.8)
8	0.2032	0.4318	66.1 (425)	69.9 (0.15)	71.5 (30.7)
9	0.2032	0.5080	55.7 (365)	58.4 (0.15)	59.7 (38.1)

implementation.

Fig. 4 gives an example of the iteration convergence of the FDM for a via with pad. Both the barrel-plate and pad-plate capacitances ( $C_b$  and  $C_p$ ) decrease and converges to stable values with the increase of iteration steps.

Fig. 5 compares the trends of  $C_b$  and  $C_p$  with different pad radius  $a$  with fixed other parameters such as the barrel, pad and anti-pad radii  $r, b$  and  $b$ . It can be seen that in the case of  $a = r$ , there is no pad-plate capacitance *i.e.*  $C_p = 0$ . With the increase of the pad radius,  $C_p$  increases while  $C_b$  decreases steadily. The total via capacitance first decreases with pad radius and then increases as pad radius becomes larger and larger.

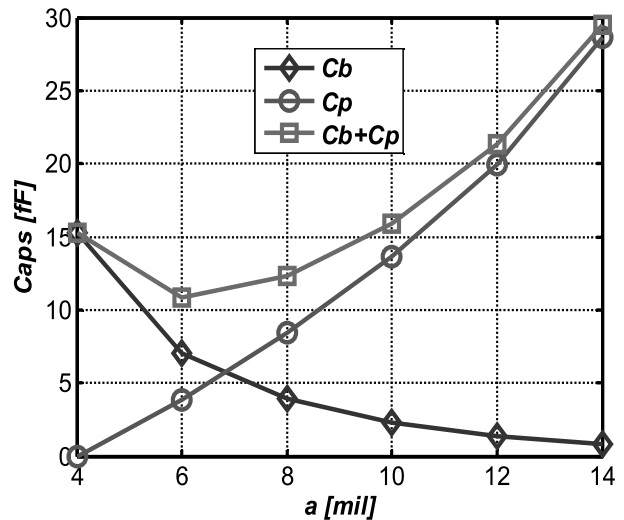


Fig. 5. The barrel-plate and pad-plate capacitances versus the pad radius with fixed other geometries. ( $r = 4, b = 20, h = 4.5$ , Unit : mil;  $\epsilon_r = 3.84$ )

Fig. 6 presents the different variations of barrel-plate and pad-plate capacitances with the separation of plates. Interestingly, the pad-plate capacitance  $C_p$  quickly reaches a maxi-

imum value when the via height or late separation  $h$  is large enough. On the other hand, the barrel-plate capacitance  $C$  increase almost linearly with the plate separation  $h$ . In the case of small plate separation,  $C_p$  dominates the via-plate capacitance while in the case of large plate separation,  $C$  is the main part of the parasitic capacitances from the via to the plate.

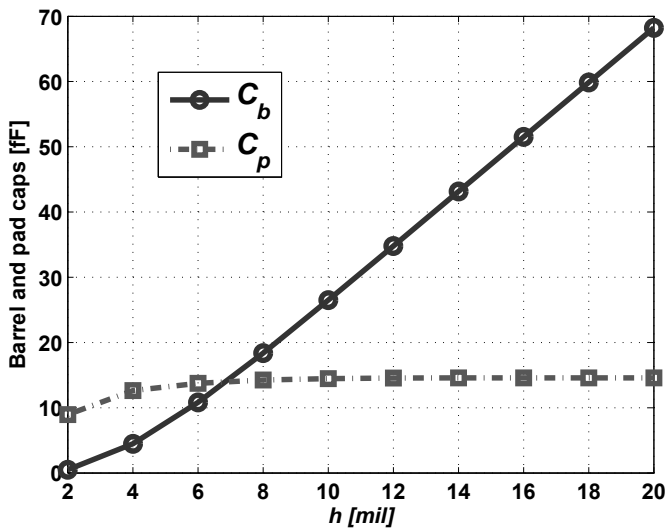


Fig. 6. The barrel-plate and pad-plate capacitances versus the plate separations with fixed other geometries. ( $r = 4, a = 8, b = 20$ , Unit : mil;  $\epsilon_r = 3.84$ )

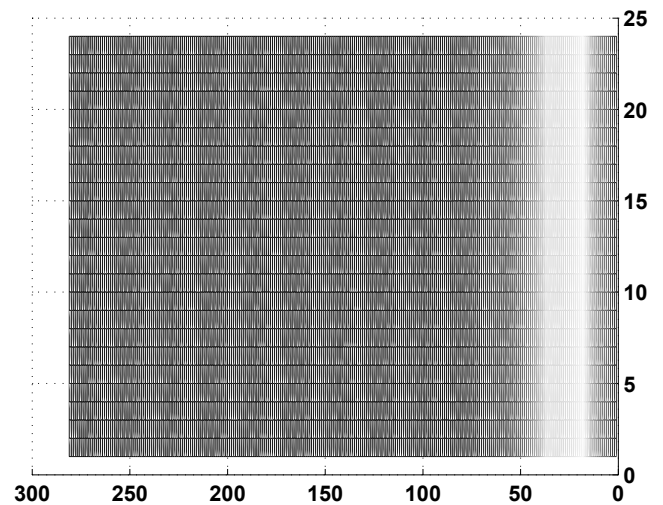
The potential distributions for a via without and with a pad have been depicted in Fig. 7 (a) and (b) respectively. For these two examples, the potentials change rapidly in the anti-pad region and its extension region along z-directions. For a via with pad, Fig. 7 (b) shows that the potentials near the anti-pad have more complicated contours. This means that the pad radial extension causes complex electric field distributions.

#### IV. CONCLUSIONS

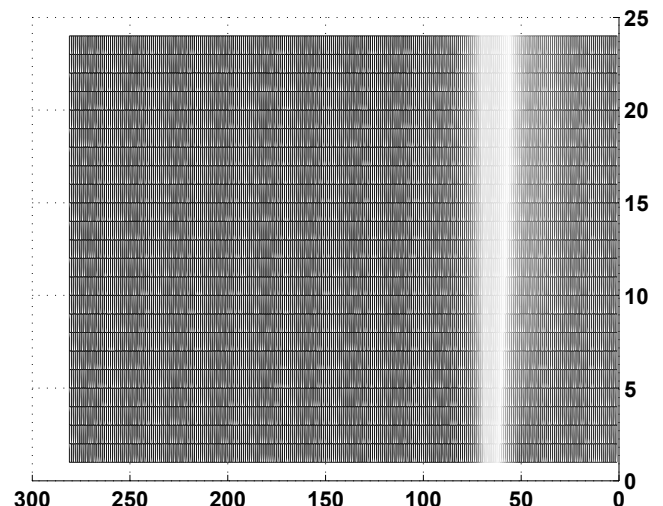
Finite difference method is used to extract the via-plate capacitance for vias with pad by solving electro-static equations. The boundary conditions are specified in the anti-pad and artificial boundaries are set to terminate the computational domain. Accuracy and efficiency have been discussed by comparing with the analytical formula for vias without pad. Variations of the parasitic capacitances with geometric parameters are investigated. Moreover, it can also be used as validations for other extraction approaches for the vias with pad.

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(a)



(b)

Fig. 7. Potential distributions for a via (a) without ( $r = a = 4$ ) and (b) with a pad ( $r = 4, a = 14$ ). ( $b = 20, h/2 = 4.5$ , unit : mil;  $\epsilon_r = 3.84$ )

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